

P54/74PCT841A/B—P54/74PCT843A/B P54/74PCT846A/B BUS INTERFACE LATCHES

PRELIMINARY

T-46-07-27



FEATURES

- Equivalent to Am29841/843/846 Bipolar Registers
- Full CMOS Implementation
- Low Power Operation
- Fully TTL Compatible Input and Output Levels
- Buffered Common Clear and Preset Input
- High Speed Parallel Latches
- Buffered Common Latch Enable Input
- Clamp Diodes on all Inputs for Ringing Suppression
- Produced with PACE Technology™
- Compact Pinout
 - 24-Pin 300 mil DIP, SOIC
 - 28-Pad 450 mil sq. LCC



DESCRIPTION

The P54/74PCT840 series bus interface latches are designed to eliminate the extra packages required to buffer existing latches and provide extra data width for wider address/data paths or buses carrying parity. The P54/74PCT841 is a buffered 10-bit wide version of the popular 'PCT373 function. The P54/74PCT843 is a 9-bit wide buffered latch with Preset (PRE) and Clear (CLR) controls making it ideal for parity bus interfacing in high-performance systems. The P54/74PCT846 is an inverting 8-bit buffered latch with all the 'PCT843 controls plus multiple enables (OE_1 , OE_2 , OE_3) to allow multiusers control of the interface, e.g., $\overline{CS}$, DMA, and $RD/\overline{WR}$. They are ideal for use as an output port requiring high I_{OL}/I_{OH} .

The P54/74PCT800 high performance interface family is designed for high-capacitance load drive capability while

providing low-capacitance bus loading at both inputs and outputs. All inputs have clamp diodes and all outputs are designed for low-capacitance bus loading in the high impedance state.

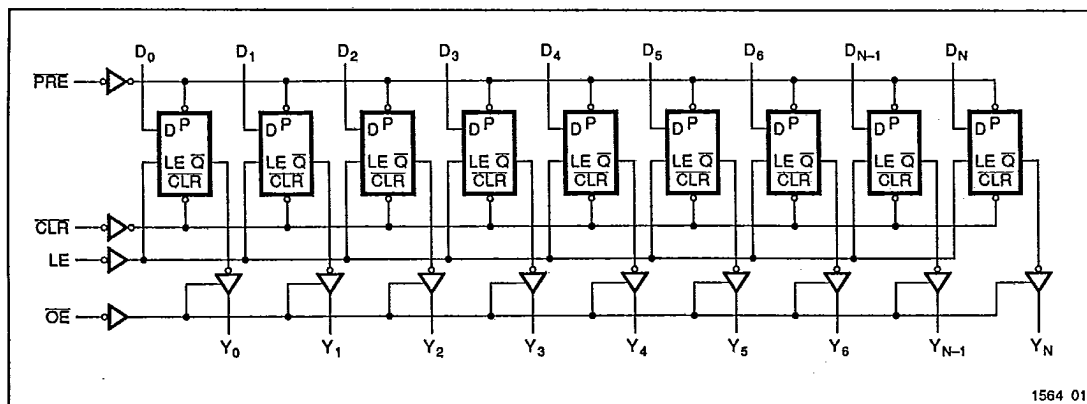
The P54/74PCT800 interface family is manufactured using PACE Technology™ which is Performance Advanced CMOS Engineered to use 0.8 micron effective channel lengths giving 500 picoseconds loaded* internal gate delays. PACE Technology includes two-level metal and epitaxial substrates. In addition to very high performance and very high density, the technology features latch-up protection, single event upset protection, and is supported by a Class 1 environment volume production facility.

* For a fan-in/fan-out of 4, at 85°C junction temperature and 5.0V.

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FUNCTIONAL BLOCK DIAGRAM



PERFORMANCE
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4-149

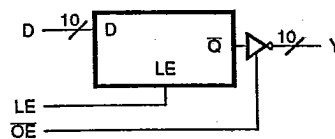
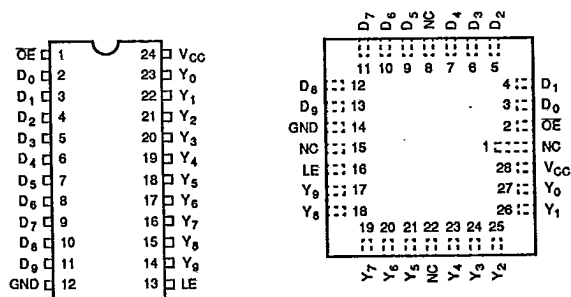
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PIN CONFIGURATIONS

LOGIC SYMBOLS

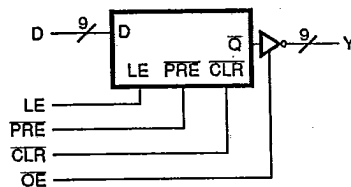
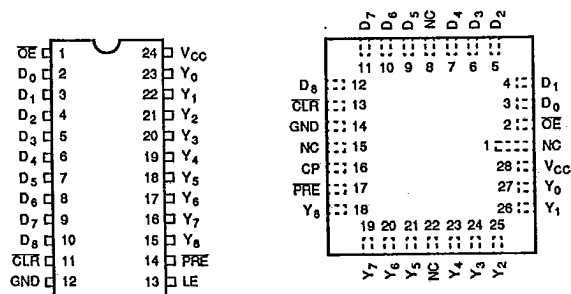
T-46-07-27

P54/74PCT841 10-BIT LATCH



1564 02

P54/74PCT843 9-BIT LATCH



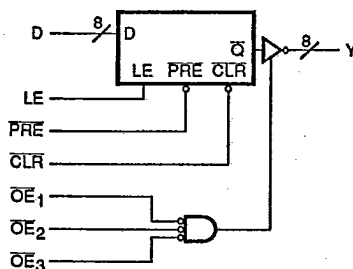
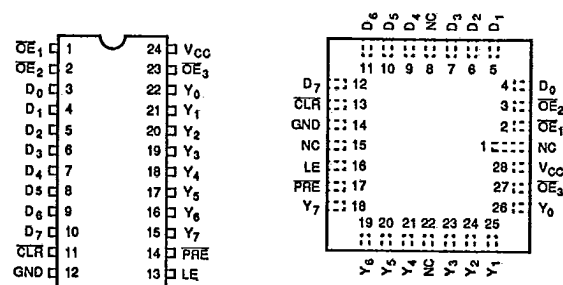
1564 03

PIN CONFIGURATIONS

LOGIC SYMBOL

T-46-07-27

P54/74PCT846 8-BIT LATCH



DIP (D4, P4) SOIC (S4)

LCC (L5-1)

1564 04

PIN DESCRIPTION

Name	I/O	Description
P54/74PCT841/43 (Non-inverting)		
$\overline{CLR}$	I	When $\overline{CLR}$ is low, the outputs are LOW if $\overline{OE}$ is LOW. When $\overline{CLR}$ is HIGH, data can be entered into the latch.
D_i	I	The latch data inputs.
LE	I	The latch enable input. The latches are transparent when LE is HIGH. Input data is latched on the HIGH-to-LOW transition.
Y_i	O	The three-state latch outputs.
$\overline{OE}$	I	The output enable control. When $\overline{OE}$ is LOW, the outputs are enabled. When $\overline{OE}$ is HIGH, the outputs Y_i are in the high-impedance (off) state.
$\overline{PRE}$	I	Preset line. When $\overline{PRE}$ is LOW, the outputs are HIGH if $\overline{OE}$ is LOW. Preset overrides $\overline{CLR}$.

1564 Tbl 01

Name	I/O	Description
P54/74PCT846 (Inverting)		
$\overline{CLR}$	I	When $\overline{CLR}$ is low, the outputs are LOW if $\overline{OE}$ is LOW. When $\overline{CLR}$ is HIGH, data can be entered into the latch.
D_i	I	The latch inverting data inputs.
LE	I	The latch enable input. The latches are transparent when LE is HIGH. Input data is latched on the HIGH-to-LOW transition.
Y_i	O	The three-state latch outputs.
$\overline{OE}$	I	The output enable control. When $\overline{OE}$ is LOW, the outputs are enabled. When $\overline{OE}$ is HIGH, the outputs Y_i are in the high-impedance (off) state.
$\overline{PRE}$	I	Preset line. When $\overline{PRE}$ is LOW, the outputs are HIGH if $\overline{OE}$ is LOW. Preset overrides $\overline{CLR}$.

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ABSOLUTE MAXIMUM RATINGS^(1,2)

Symbol	Parameter	Value	Unit
T _{STG}	Storage Temperature	-65 to +150	°C
T _A	Ambient Temperature Under Bias	-55 to +125	°C
V _{CC}	V _{CC} Potential to Ground	-0.5 to +7.0	V
I _{IN}	Input Current	-30 to +5.0	mA

Notes: 1564 Tbl 03
1. Operation beyond the limits set forth in the above table may impair the useful life of the device. Unless otherwise noted, these limits are over the operating free-air temperature range.

Symbol	Parameter	Value	Unit
I _{OUTPUT}	Current Applied to Output	100	mA
V _{IN}	Input Voltage	-0.5 to V _{CC} + 0.5	V
V _{OUT}	Voltage Applied to Output	-0.5 to V _{CC} + 0.5	V

1564 Tbl 04
2. Unused inputs must always be connected to an appropriate logic voltage level, preferably either V_{CC} or ground.

RECOMMENDED OPERATING CONDITIONS

Free Air Ambient Temperature	Min	Max
Military	-55°C	+125°C
Commercial	0°C	+70°C

1564 Tbl 05

Supply Voltage (V _{CC})	Min	Max
Military	+4.5V	+5.5V
Commercial	+4.75V	+5.25V

1564 Tbl 06

DC ELECTRICAL CHARACTERISTICS (Over recommended operating conditions)

Symbol	Parameter	Min	Typ ¹	Max	Units	V _{CC}	Conditions
V _{IH}	Input HIGH Voltage	2.0		V _{CC} + 0.5	V		
V _{IL}	Input LOW Voltage	-0.5		0.8	V		
V _H	Hysteresis		.35		V		All inputs
V _{CD}	Input Clamp Diode Voltage			-1.2	V	MIN	I _{IN} = -18mA
V _{OH}	Output HIGH Voltage	V _{CC} = 3V, V _{IN} = 0.2V, or V _{CC} - 0.2V		V _{CC} - 0.2	V		I _{OH} = -32μA
		Military/Commercial (CMOS)		V _{CC} - 0.2	V	MIN	I _{OH} = -300μA
		Military (TTL)		2.4	V	MIN	I _{OH} = -15mA
		Commercial (TTL)		2.7	V	MIN	I _{OH} = -24mA
V _{OL}	Output LOW Voltage	V _{CC} = 3V, V _{IN} = 0.2V, or V _{CC} - 0.2V		0.2	V		I _{OL} = 300μA
		Military/Commercial (CMOS)		0.2	V	MIN	I _{OL} = 300μA
		Military (TTL)		0.5	V	MIN	I _{OL} = 32mA
		Commercial (TTL)		0.5	V	MIN	I _{OL} = 48mA
I _{IH}	Input HIGH Current			5	μA	MAX	V _{IN} = V _{CC}
I _{IL}	Input LOW Current			-5	μA	MAX	V _{IN} = GND
I _{IH}	Input HIGH Current ³			5	μA	MAX	V _{IN} = 2.7V
I _{IL}	Input LOW Current ³			-5	μA	MAX	V _{IN} = 0.5V
I _{OZH}	Off State I _{OUT} HIGH-Level Voltage Applied			10	μA	MAX	V _{OUT} = V _{CC}
I _{OZL}	Off State I _{OUT} LOW-Level Voltage Applied			-10	μA	MAX	V _{OUT} = GND
I _{OZH}	Off State I _{OUT} HIGH-Level Voltage Applied ³			10	μA	MAX	V _{OUT} = 2.7V
I _{OZL}	Off State I _{OUT} LOW-Level Voltage Applied ³			-10	μA	MAX	V _{OUT} = 0.5V
I _{OS}	Output Short Circuit Current ²	-75			mA	MAX	V _{OUT} = 0.0V
C _{IN}	Input Capacitance ³		5	10	pF	MAX	All inputs
C _{OUT}	Output Capacitance ³		9	12	pF	MAX	All outputs

Notes:

1. Typical limits are at V_{CC} = 5.0V, T_A = +25°C ambient.
2. Not more than one output should be shorted at a time. Duration of short should not exceed one second. The use of high speed test apparatus and/or sample and hold techniques are preferable in order to minimize internal chip heating and more accurately reflect

operational values. Otherwise prolonged shorting of a high output may raise the chip temperature well above normal and thereby cause invalid readings in other parameter tests. In any sequence of parameter tests, I_{OS} tests should be performed last.

3. This parameter is guaranteed but not tested.

1564 Tbl 07

DC CHARACTERISTICS (Over recommended operating conditions unless otherwise specified.)

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Symbol	Parameter	Typ ¹	Max	Units	Conditions
I_{CCOQ}	Quiescent Power Supply Current (CMOS inputs) Com'l Mil	.003 .003	0.3 0.5	mA mA	$V_{CC} = \text{MAX}$, $V_{IN} \leq 0.2V$ or $V_{IN} \geq V_{CC} - 0.2V$, $f = 0$, Outputs Open
I_{CCQT}	Quiescent Power Supply Current (TTL inputs)		2.0	mA	$V_{CC} = \text{MAX}$, $V_{IN} = 3.4V^2$, $f = 0$, Outputs Open
I_{CCD}	Dynamic Power Supply Current ³		0.25	mA/ mHz	$V_{CC} = \text{MAX}$, One Input Toggling, 50% Duty Cycle, $\overline{OE} = \text{GND}$, $V_{IN} \leq 0.2V$ or $V_{IN} \geq V_{CC} - 0.2V$, Outputs Open, $LE = V_{CC}$
I_{CC}	Total Power Supply Current ⁵		4.0	mA	$V_{CC} = \text{MAX}$, $LE = V_{CC}$, 50% Duty Cycle, Outputs Open, One Bit Toggling at $f_1 = 10\text{MHz}$, $\overline{OE} = \text{GND}$ and $V_{IN} \leq 0.2V$ or $V_{IN} \geq V_{CC} - 0.2V$
			5.0	mA	$V_{CC} = \text{MAX}$, $LE = V_{CC}$, 50% Duty Cycle, Outputs Open, One Bit Toggling at $f_1 = 10\text{mHz}$, $\overline{OE} = \text{GND}$ and $V_{IN} = 3.4V$ or $V_{IN} = \text{GND}$
			6.5 ⁴	mA	$V_{CC} = \text{MAX}$, $LE = V_{CC}$, 50% Duty Cycle, Outputs Open, Eight Bits Toggling at $f_1 = 2.5\text{MHz}$, $\overline{OE} = \text{GND}$ and $V_{IN} \leq 0.2V$ or $V_{IN} \geq V_{CC} - 0.2V$
			14.5 ⁴	mA	$V_{CC} = \text{MAX}$, $LE = V_{CC}$, 50% Duty Cycle, Outputs Open, Eight Bits Toggling at $f_1 = 2.5\text{MHz}$, $\overline{OE} = \text{GND}$ and $V_{IN} = 3.4V$ or $V_{IN} = \text{GND}$

Notes:

- Typical values are at $V_{CC} = 5.0V$, $+25^\circ\text{C}$ ambient and maximum loading.
- Per TTL driven Input ($V_{IN} = 3.4V$); all other inputs at V_{CC} or GND.
- This parameter is not directly testable, but is derived for use in Total Power Supply calculations.
- Values for these conditions are examples of the I_{CC} formula. These limits are guaranteed but not tested.
- $I_{CC} = I_{\text{QUIESCENT}} + I_{\text{INPUTS}} + I_{\text{DYNAMIC}}$
 $I_{CC} = I_{CCOQ} + I_{CCQT} D_H N_I + I_{CCD} (f_1/2 + f_1 N_I)$
 I_{CCOQ} = Quiescent Current with CMOS input levels

I_{CCQT} = Power Supply Current for a TTL High Input ($V_{IN} = 3.4V$)
 D_H = Duty Cycle for TTL Inputs High
 N_I = Number of TTL Inputs at D_H
 I_{CCD} = Dynamic Current Caused by an Input Transition Pair (HLH or LHL)
 f_1 = Clock Frequency for Register Devices (Zero for Non-Register Devices)
 f_1 = Input Frequency
 N_I = Number of Inputs at f_1
 All currents are in milliamps and all frequencies are in megahertz.

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AC CHARACTERISTICS

T-46.07-27

Symbol	Parameter	Test Conditions	P54/74PCT841A-846A				P54/74PCT841B-846B				Units	Fig. No.
			MIL		COM'L		MIL		COM'L			
			Min. ¹	Max.	Min. ¹	Max.	Min. ¹	Max.	Min. ¹	Max		
t_{PLH} t_{PHL}	Data (D_i) to Output (Y_i) (LE = HIGH)	$C_L = 50\text{pF}$ $R_L = 500\Omega$	—	11.0 ²	—	9.5 ²	—	7.5 ²	—	6.5 ²	ns	1
			—	11.0	—	9.5	—	7.5	—	6.5	ns	5
t_{PLH} t_{PHL}	Data (D_i) to Output (Y_i) (LE = HIGH)	$C_L = 300\text{pF}^4$ $R_L = 500\Omega$	—	15.0	—	13.0	—	15.0	—	13.0	ns	1
			—	15.0	—	13.0	—	15.0	—	13.0	ns	5
t_{PLH} t_{PHL}	Latch Enable (LE) to Y_i	$C_L = 50\text{pF}$ $R_L = 500\Omega$	—	16.0	—	12.0	—	10.5	—	8.0	ns	1
			—	16.0	—	12.0	—	10.5	—	8.0	ns	6
t_{PLH} t_{PHL}	Latch Enable (LE) to Y_i	$C_L = 300\text{pF}^4$ $R_L = 500\Omega$	—	20.0	—	16.0	—	18.0	—	15.5	ns	1
			—	20.0	—	16.0	—	18.0	—	15.5	ns	6
t_{PLH}	Propagation Delay Preset to Y_i	$C_L = 50\text{pF}$ $R_L = 500\Omega$	—	14.0	—	12.0	—	10.0	—	8.0	ns	1
			—	14.0	—	12.0	—	10.0	—	8.0	ns	5
t_{PHL}	Propagation Delay Clear to Y_i		—	15.0	—	13.0	—	11.0	—	10.0	ns	1
			—	15.0	—	13.0	—	11.0	—	10.0	ns	5
t_{PZH} t_{PZL}	Output Enable Time OE ↓ to Y_i	$C_L = 50\text{pF}$ $R_L = 500\Omega$	—	15.0	—	14.0	—	8.5	—	8.0	ns	1, 7,
			—	15.0	—	14.0	—	8.5	—	8.0	ns	8
t_{PZH} t_{PZH}	Output Enable Time OE ↓ to Y_i		—	15.0	—	14.0	—	8.5	—	8.0	ns	8
t_{PZH} t_{PLZ}	Output Disable Time OE ↑ to Y_i	$C_L = 5\text{pF}^4$ $R_L = 500\Omega$	—	10.0	—	9.0	—	6.5	—	6.0	ns	1, 7,
			—	10.0	—	9.0	—	6.5	—	6.0	ns	8
t_{PHZ} t_{PLZ}	Output Disable Time OE ↑ to Y_i	$C_L = 50\text{pF}$ $R_L = 500\Omega$	—	12.0	—	12.0	—	7.5	—	7.0	ns	1, 7,
			—	12.0	—	12.0	—	7.5	—	7.0	ns	8
t_{PLH} t_{PHL}	DATA (D_i) to Output (Y_i) (LE = HIGH)		—	12.0 ³	—	10.0 ³	—	9.0 ³	—	8.0 ³	ns	1
			—	12.0	—	10.0	—	9.0	—	8.0	ns	5

1564 Tbl 09

AC OPERATING REQUIREMENTS

Symbol	Parameter	Test Conditions	P54/74PCT841A-846A				P54/74PCT841B-846B				Units	Fig. No.
			MIL		COM'L		MIL		COM'L			
			Min. ¹	Max.	Min. ¹	Max.	Min. ¹	Max.	Min. ¹	Max.		
t _{su}	Data to LE Set-up Time	C _L = 50pF R _L = 500Ω	2.5	—	2.5	—	2.5	—	2.5	—	ns	9
t _H	Data to LE Hold Time		3.0	—	2.5	—	2.5	—	2.5	—	ns	9
t _{su}	Preset Recovery (PRE ↑) Time		—	17.0	—	14.0	—	13.0	—	10.0	ns	9
t _{su}	Clear Recover (CLR ↑) Time		—	17.0	—	14.0	—	10.0	—	10.0	ns	9
t _{w(H)}	LE Pulse Width HIGH		6.0	—	6.0	—	4.0	—	4.0	—	ns	5
t _{w(L)}	Preset Pulse Width LOW		9.0	—	8.0	—	4.0	—	4.0	—	ns	5
t _{w(L)}	Clear Pulse Width LOW		9.0	—	8.0	—	4.0	—	4.0	—	ns	5

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Notes:

1. Minimum limits are guaranteed but not tested on Propagation Delays.
2. These limits do not apply to the P54/74PCT846.
3. Limits for P54/74PCT846.
4. This parameter is guaranteed but not tested.

FUNCTION TABLES[§]

P54/74PCT841/43

T-46-07-27

Inputs					Internal	Outputs	Function
CLR	PRE	OE	LE	D _i	O _i	Y _i	
H	H	H	X	X	X	Z	High Z
H	H	H	H	L	L	Z	High Z
H	H	H	H	H	H	Z	High Z
H	H	H	L	X	NC	Z	Latched (High Z)
H	H	L	H	L	L	L	Transparent
H	H	L	H	H	H	H	Transparent
H	H	L	L	X	NC	NC	Latched
H	L	L	X	X	H	H	Preset
L	H	L	X	X	L	L	Clear
L	L	L	X	X	H	H	Preset
L	H	H	L	X	L	Z	Latched (High Z)
H	L	H	L	X	H	Z	Latched (High Z)

§ H = HIGH, L = LOW, X = Don't care, NC = No Change, Z = High Impedance.

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FUNCTION TABLES[§]

P54/74PCT841/46

Inputs					Internal	Outputs	Function
CLR	PRE	OE	LE	D _i	O _i	Y _i	
H	H	H	X	X	X	Z	High Z
H	H	H	H	H	L	Z	High Z
H	H	H	H	L	H	Z	High Z
H	H	H	L	X	NC	Z	Latched (High Z)
H	H	L	H	H	L	L	Transparent
H	H	L	H	L	H	H	Transparent
H	H	L	L	X	NC	NC	Latched
H	L	L	X	X	H	H	Preset
L	H	L	X	X	L	L	Clear
L	L	L	X	X	H	H	Preset
L	H	H	L	X	L	Z	Latched (High Z)
H	L	H	L	X	H	Z	Latched (High Z)

§ H = HIGH, L = LOW, X = Don't care, NC = No Change, Z = High Impedance.

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★ ORDERING INFORMATION T-46-07-27

PxxPCT Temp. Range	xxxx Device Type	x Package	x Process	
			B	MIL-STD-883, Class B
			P	Plastic DIP
			D	CERDIP
			S	Small Outline IC
			L	Leadless Chip Carrier
			841A	10-Bit Non-Inverting Latch
			843A	9-Bit Non-Inverting Latch
			846A	8-Bit Inverting Latch
			841B	Fast 10-Bit Non-Inverting Latch
			843B	Fast 9-Bit Non-Inverting Latch
			846B	Fast 8-Bit Inverting Latch
			74	Commercial
			54	Military

1564 05

TECHDOC 1564